BGS8U5

SiGe:C low-noise amplifier with bypass switch for LTE/5G NR
Rev. 5 — 1 December 2021 Product data sheet

1 General description

The BGS8U5, also known as the LTE3301U, is a Low-Noise Amplifier (LNA) with bypass switch for LTE, and 5G NR receiver applications. It is available in a small plastic 6-pin thin leadless package.

The BGS8U5 delivers system-optimized gain for LTE bands 42 and 43 where sensitivity improvement is required. Complete 5G NR bands n77, n78, and n79 are supported. When receive signal strength is sufficient, the BGS8U5 can be switched off to operate in bypass mode. Switching to bypass mode results into an increased IP3 $_{\rm i}$ level and supply current in bypass mode at 1 μ A. The BGS8U5 requires only one external matching inductor up to 4200 MHz.

The BGS8U5 is optimized for 3300 MHz to 4200 MHz, and with one additional output matching inductor optimized for 4400-5000 MHz.

2 Features and benefits

- Operating frequency from 3300 MHz to 5000 MHz
- Noise figure 1.0 dB
- Gain 15 dB
- High input 1 dB compression point -8 dBm
- High in band IP3_i 4 dBm
- Bypass switch insertion loss -3.2 dB
- Supply voltage 1.5 V to 3.1 V
- Integrated RF supply decoupling capacitor
- Optimized performance at a supply current 4.7 mA
- Bypass mode current consumption < 1 μA
- · Integrated temperature stabilized bias for easy design
- · Requires only one input matching inductor
- Input and output AC coupled through DC blocking capacitors
- Integrated matching for the output (LTE B42/43, 5G NR n77/n78)
- ESD protection on all pins
- · Low Bill of Materials (BOM)
- 6-pins leadless package; 1.1 mm x 0.7 mm x 0.37 mm; 0.4 mm pitch
- 180 GHz transit frequency SiGe:C technology
- · Moisture sensitivity level 1



SiGe:C low-noise amplifier with bypass switch for LTE/5G NR

3 Applications

- LNA for LTE and 5G NR reception in smart phones
- feature phones
- tablet PCs
- · RF front-end modules

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4 Quick reference data

Table 1. Quick reference data

f = 3800 MHz; V_{CC} = 2.8 V; T_{amb} = 25 °C. Input matched to 50 Ω using application diagram from Figure 3 and component values as in Table 12. Unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
I _{CC}	supply current	in gain mode		-	4.7	6.0	mA
		in bypass mode		-	-	1.0	μΑ
Gp	power gain	in gain mode		13.0	15.0	17.0	dB
		in bypass mode		-4.0	-3.2	-2.4	dB
NF	noise figure		[1] [2]	-	1.0	1.3	dB
P _{i(1dB)}	input power at 1 dB gain compression	in gain mode	[1]	-9.5	-8.0	-	dBm
IP3 _i	input third-order intercept point	in gain mode; Δf = 1 MHz/10 MHz	[1]	1.0	4.0	-	dBm

^[1] Guaranteed by design; not tested in production

5 Ordering information

Table 2. Ordering information

Type number	Package		
	Name	Description	Version
BGS8U5	XSON6	plastic extremely thin small outline package; no leads; 6 terminals; body 1.1 mm x 0.7 mm x 0.37 mm	SOT1232

6 Marking

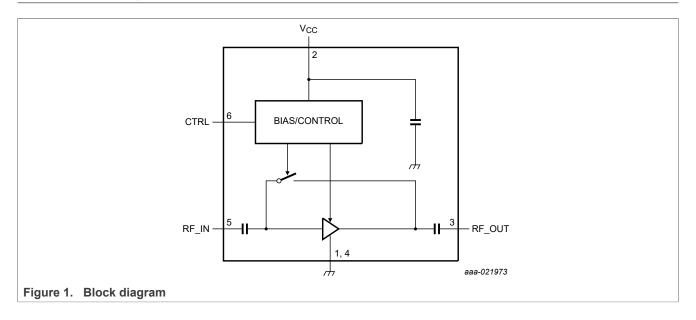
Table 3. Marking code

Type number	Marking code
BGS8U5	Т

^[2] PCB losses are subtracted.

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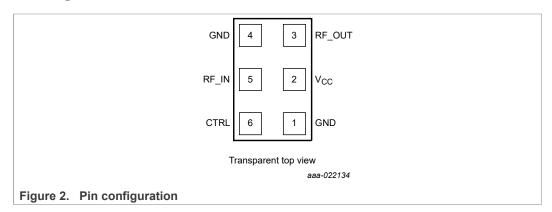
7 Block diagram



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8 Pinning information

8.1 Pinning



8.2 Pin description

Table 4. Pinning

Symbol	Pin	Description
GND	1	RF ground
V _{CC}	2	supply voltage
RF_OUT	3	RF out
GND	4	RF ground
RF_IN	5	RF in
CTRL	6	gain control, switch between gain and bypass mode

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9 Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). See Section 18.3 "Disclaimers", paragraph 'Limiting values'.

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		-0.5	+5.0	V
V _{I(CTRL)}	input voltage on pin CTRL	V _{I(CTRL)} < V _{CC} + 0.6 V	-0.5	+5.0	V
V _{I(RF_IN)}	input voltage on pin RF_IN	DC; $V_{I(RF_IN)} < V_{CC} + 0.6 V$ [1]	-0.5	+5.0	V
V _{I(RF_OUT)}	input voltage on pin RF_OUT	DC; $V_{I(RF_OUT)} < V_{CC} + 0.6 V$ [1]	-0.5	+5.0	V
P _{i(RF)CW}	continuous waveform RF input	RF	-	26.0	dBm
	power	RF [2]	-	20.0	dBm
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	+150	°C
V _{ESD}	electrostatic discharge voltage	Human Body Model (HBM) according to ANSI/ESDA/JEDEC standard JS-001	-	±2	kV
		Charged Device Model (CDM) according to ANSI/ESDA/JEDEC standard JS-002	-	±1	kV

^[1] The RF input and output are AC coupled through internal DC blocking capacitors.

10 Recommended operating conditions

Table 6. Characteristics

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{CC}	supply voltage			1.5	-	3.1	V
T _{amb}	ambient temperature			-40	+25	+85	°C
V _{I(CTRL)}	input voltage on pin CTRL	bypass mode	[1]	0.0	-	0.25	V
		gain mode	[1]	8.0	-	V_{CC}	V

^[1] $V_{I(CTRL)}$ shall be applied only after V_{cc} is applied to the device

11 Thermal characteristics

Table 7. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
R _{th(j-sp)}	thermal resistance from junction to solder point		225	K/W

BGS8U5

^[2] $f = 3600 \text{ MHz}, 200 \text{ hrs at } T_{amb} = 100 ^{\circ}\text{C}$

^[3] HBM ESD protection level is according to JS-001 classification 2 (2000 V to < 4000 V)

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12 Characteristics

Table 8. Characteristics

3400 MHz \leq f \leq 4200 MHz; V_{CC} = 1.8 V; T_{amb} = 25 °C; input matched 50 Ω using application diagram from Figure 3 and component values as in Table 12. Unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Gain mod	le						
I _{CC}	supply current	V _{I(CTRL)} > 0.8 V		-	4.5	6.0	mA
Gp	power gain	f = 3400 MHz		14.0	16.0	18.0	dB
		f = 3800 MHz		12.5	14.5	16.5	dB
		f = 4200 MHz		11.0	13.0	15.0	dB
ΔG/ΔT	gain variation with temperature		[1]	-	-0.01	-	dB/°C
NF	noise figure	f = 3400 MHz	[1] [2]		1.0	1.3	dB
		f = 3800 MHz	[1] [2]		1.0	1.3	dB
		f = 4200 MHz	[1] [2]		1.0	1.3	dB
P _{i(1dB)}	input power at 1 dB gain	f = 3400 MHz		-13.0	-11.5	-	dBm
	compression	f = 3800 MHz	[1]	-11.5	-10.0	-	dBm
		f = 4200 MHz	[1]	-10.5	-9.0	-	dBm
P _{o(1dB)}	output power	f = 3400 MHz	[1]	-	3.5	-	dBm
	at 1 dB gain compression	f = 3800 MHz	[1]	-	3.5	-	dBm
		f = 4200 MHz	[1]	-	3.5	-	dBm
IP3 _i	input third-order intercept point	f = 3400 MHz; Δf = 1 MHz/10 MHz	[1]	-2.0	1.0	-	dBm
		f = 3800 MHz; Δf = 1 MHz/10 MHz	[1]	-1.0	2.0	-	dBm
		f = 4200 MHz; Δf = 1 MHz/10 MHz	[1]	-1.0	2.0	-	dBm
RLin	input return loss	f = 3400 MHz		9.0	12.0	-	dB
		f = 3800 MHz		9.0	12.0	-	dB
		f = 4200 MHz		-	22.0	-	dB
RLout	output return loss	f = 3400 MHz		9.0	12.0	-	dB
		f = 3800 MHz		9.0	12.0	-	dB
		f = 4200 MHz		-	9.0	-	dB
ISL	isolation	f = 3400 MHz		20.0	22.0	24.0	dB
		f = 3800 MHz		20.0	22.0	24.0	dB
		f = 4200 MHz		20.0	22.0	24.0	dB
K	Rollett stability factor	f = 10 MHz - 10 GHz	[1]	1	-	-	-
t _{on}	turn-on time	time from $V_{I(CTRL)}$ ON to 90 % of the gain	[1]		0.5	1.0	μs
t _{off}	turn-off time	time from $V_{I(CTRL)}$ OFF to 10 % of the gain	[1]	-	0.35	1.0	μs

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Table 8. Characteristics...continued

3400 MHz \leq f \leq 4200 MHz; V_{CC} = 1.8 V; T_{amb} = 25 °C; input matched 50 Ω using application diagram from Figure 3 and component values as in Table 12. Unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Bypass m	node						
I _{CC}	supply current	V _{I(CTRL)} < 0.25 V		-	-	1.0	μA
Gp	power gain	f = 3400 MHz		-4.2	-3.4	-2.6	dB
		f = 3800 MHz		-4.2	-3.4	-2.6	dB
		f = 4200 MHz		-5.0	-4.2	-3.4	dB
ISL	isolation	f = 3400 MHz		2.6	3.4	4.2	dB
		f = 3800 MHz		2.6	3.4	4.2	dB
		f = 4200 MHz		3.4	4.2	5.0	dB
P _{i(1dB)}		f = 3400 MHz	[1]	5.5	7.0	-	dBm
	compression	f = 3800 MHz	[1]	6.0	7.5	-	dBm
		f = 4200 MHz	[1]	5.5	7.0	-	dBm
IP3 _i	input third-order intercept point	f = 3400 MHz	[1]	20.5	23.5	-	dBm
		f = 3800 MHz	[1]	19.0	22.0	-	dBm
		f = 4200 MHz	[1]	18.0	21.0	-	dBm
RLin	input return loss	f = 3400 MHz		6.5	8.0	-	dB
		f = 3800 MHz		7.5	9.0	-	dB
		f = 4200 MHz		7.5	9.0	-	dB
RL _{out}	output return loss	f = 3400 MHz		5.5	7.0	-	dB
		f = 3800 MHz		6.5	8.0	-	dB
		f = 4200 MHz		6.5	8.0	-	dB
Δφ _{S21}	gain phase step variation	between gain mode and bypass					
		f = 3400 MHz		-5.0	-	+5.0	deg
		f = 3800 MHz	[1]	-5.0	-	+5.0	deg
		f = 4200 MHz	[1]	-5.0	-	+5.0	deg

Guaranteed by design; not tested in production PCB losses are subtracted.

SiGe:C low-noise amplifier with bypass switch for LTE/5G NR

Table 9. Characteristics

3400 MHz \leq f \leq 4200 MHz; V_{CC} = 2.8 V; T_{amb} = 25 °C; input matched 50 Ω using application diagram from Figure 3 and component values as in Table 12. Unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Gain mod	e						
I _{CC}	supply current	V _{I(CTRL)} > 0.8 V		-	4.7	6.0	mA
G _p	power gain	f = 3400 MHz		14.5	16.5	18.5	dB
		f = 3800 MHz		13.0	15.0	17.0	dB
		f = 4200 MHz		11.5	13.5	15.5	dB
ΔG/ΔT	gain variation with temperature		[1]	_	-0.01	-	dB/°C
NF	noise figure	f = 3400 MHz	[1] [2]	-	1.0	1.3	dB
		f = 3800 MHz	[1] [2]		1.0	1.3	dB
		f = 4200 MHz	[1] [2]		1.0	1.3	dB
P _{i(1dB)}	input power at 1 dB gain	f = 3400 MHz		-11.0	-9.5	-	dBm
	compression	f = 3800 MHz	[1]	-9.5	-8.0	-	dBm
		f = 4200 MHz		-7.5	-6.0	-	dBm
P _{o(1dB)}	output power at	f = 3400 MHz	[1]	-	6.0	-	dBm
	1 dB gain compression	f = 3800 MHz	[1]		6.0	-	dBm
		f = 4200 MHz	[1]	-	6.0	-	dBm
IP3 _i	input third-order intercept point	$f = 3400 \text{ MHz}$; $\Delta f = 1 \text{ MHz}/10 \text{ MHz}$	[1]	1.0	2.0	-	dBm
		$f = 3800 \text{ MHz}$; $\Delta f = 1 \text{ MHz}/10 \text{ MHz}$	[1]	1.0	4.0	-	dBm
		$f = 4200 \text{ MHz}$; $\Delta f = 1 \text{ MHz}/10 \text{ MHz}$	[1]	1.0	4.0	-	dBm
RL_{in}	input return loss	f = 3400 MHz		9.0	12.0	-	dB
		f = 3800 MHz		9.0	12.0	-	dB
		f = 4200 MHz		-	22.0	-	dB
RL _{out}	output return loss	f = 3400 MHz		9.0	12.0	-	dB
		f = 3800 MHz		9.0	12.0	-	dB
		f = 4200 MHz		-	9.0	-	dB
ISL	isolation	f = 3400 MHz		20.0	22.0	24.0	dB
		f = 3800 MHz		20.0	22.0	24.0	dB
		f = 4200 MHz		20.0	22.0	24.0	dB
K	Rollett stability factor	f = 10 MHz - 10 GHz	[1]		-	-	-
t _{on}	turn-on time	time from $V_{I(\mbox{\footnotesize{CTRL}})}$ ON, to 90 % of the gain	[1]		0.4	1.0	μs
t _{off}	turn-off time	time from $V_{I(CTRL)}$ OFF, to 10 % of the gain	[1]	-	0.25	1.0	μs

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Table 9. Characteristics ...continued

3400 MHz \leq f \leq 4200 MHz; V_{CC} = 2.8 V; T_{amb} = 25 °C; input matched 50 Ω using application diagram from Figure 3 and component values as in Table 12. Unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Bypass m	node						
I _{CC}	supply current	V _{I(CTRL)} < 0.25 V		-	-	1.0	μΑ
Gp	power gain	f = 3400 MHz		-4.0	-3.2	-2.4	dB
		f = 3800 MHz		-4.0	-3.2	-2.4	dB
		f = 4200 MHz		-4.8	-4.0	-3.2.	dB
ISL	isolation	f = 3400 MHz		2.4	3.2	4.0	dB
		f = 3800 MHz		2.4	3.2	4.0	dB
		f = 4200 MHz		3.2	4.0	4.8	dB
P _{i(1dB)}		f = 3400 MHz	[1]	5.5	7.0	-	dBm
	compression	f = 3800 MHz	[1]	6.0	7.5	-	dBm
		f = 4200 MHz	[1]	5.5	7.0	-	dBm
IP3 _i	input third-order intercept point	f = 3400 MHz	[1]	20.5	23.5	-	dBm
		f = 3800 MHz	[1]	19.0	22.0	-	dBm
		f = 4200 MHz	[1]	18.0	21.0	-	dBm
RLin	input return loss	f = 3400 MHz		6.5	8.0	-	dB
		f = 3800 MHz		7.5	9.0	-	dB
		f = 4200 MHz		7.5	9.0	-	dB
RL _{out}	output return loss	f = 3400 MHz		5.5	7.0	-	dB
		f = 3800 MHz		6.5	8.0	-	dB
		f = 4200 MHz		6.5	8.0	-	dB
Δφ _{S21}	gain phase step variation	between gain mode and bypass m	node				_
		f = 3400 MHz	[1]	-0.0	-	+5.0	deg
		f = 3800 MHz		-5.0	-	+5.0	deg
		f = 4200 MHz	[1]	-5.0	-	+5.0	deg

Guaranteed by design; not tested in production PCB losses are subtracted.

SiGe:C low-noise amplifier with bypass switch for LTE/5G NR

Table 10. Characteristics

4400 MHz \leq f \leq 5000 MHz; V_{CC} = 1.8 V; T_{amb} = 25 °C; input matched 50 Ω using application diagram from Figure 4 and component values as in Table 13. Unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gain mod	le					
G _p	power gain	f = 4400 MHz	-	12.5	-	dB
		f = 5000 MHz	-	10.0	-	dB
NF	noise figure	f = 4400 MHz [1]		1.0	-	dB
		f = 5000 MHz [1]	-	1.3	-	dB
P _{i(1dB)}	input power at 1 dB gain	f = 4400 MHz	-	-8.5	-	dBm
	compression	f = 5000 MHz	-	-7.5	-	dBm
P _{o(1dB)}	output power	f = 4400 MHz	-	2.5	-	dBm
	at 1 dB gain compression	f = 5000 MHz	-	1.0	-	dBm
IP3 _i	input third-order intercept point	f = 4400 MHz; Δf = 1 MHz/10 MHz	-	2.0	-	dBm
		f = 5000 MHz; Δf = 1 MHz/10 MHz	-	2.0	-	dBm
RLin	input return loss	f = 4400 MHz	-	17.0	-	dB
		f = 5000 MHz	-	14.0	-	dB
RL _{out}	output return loss	f = 4400 MHz	-	15.0	-	dB
		f = 5000 MHz	-	10.0	-	dB
ISL	isolation	f = 4400 MHz	-	22.0	-	dB
		f = 5000 MHz	-	22.0	-	dB
Bypass m	node					
G _p	power gain	f = 4400 MHz	-	-3.8	-	dB
		f = 5000 MHz	-	-7.2	-	dB
ISL	isolation	f = 4400 MHz	-	3.8	-	dB
		f = 5000 MHz	-	7.2	-	dB
P _{i(1dB)}	input power at 1 dB gain	f = 4400 MHz	-	7.0	-	dBm
	compression	f = 5000 MHz	-	6.0	-	dBm
IP3 _i	input third-order intercept point	f = 4400 MHz	-	22.0	-	dBm
		f = 5000 MHz	-	19.0	-	dBm
RL _{in}	input return loss	f = 4400 MHz	-	10.0	-	dB
		f = 5000 MHz	-	6.0	-	dB
RL _{out}	output return loss	f = 4400 MHz	-	22.0	-	dB
		f = 5000 MHz	-	21.0	-	dB
Δφ _{S21}	gain phase step variation	between gain mode and bypass mode		,		,
		f = 4400 MHz [2]	-5.0	-	+5.0	deg
		f = 5000 MHz [2]	-5.0	-	+5.0	deg

^[1] PCB losses are subtracted.

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[2] Guaranteed by design; not tested in production

Table 11. Characteristics

4400 MHz \leq f \leq 5000 MHz; V_{CC} = 2.8 V; T_{amb} = 25 °C; input matched 50 Ω using application diagram from Figure 4 and component values as in Table 13. Unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gain mod	le				-	
Gp	power gain	f = 4400 MHz	-	13.0	-	dB
		f = 5000 MHz	-	10.5	-	dB
NF	noise figure	f = 4400 MHz [1]	-	1.0	-	dB
·	f = 5000 MHz [1]	-	1.3	-	dB	
P _{i(1dB)}	input power at 1 dB gain	f = 4400 MHz	-	-6.0	-	dBm
	compression	f = 5000 MHz	-	-5.0	-	dBm
P _{o(1dB)} output power at 1 dB gain com		f = 4400 MHz	-	5.0	-	dBm
	at 1 dB gain compression	f = 5000 MHz	-	4.5	-	dBm
IP3 _i	input third-order intercept point	f = 4400 MHz; Δf = 1 MHz/10 MHz	- 5.0 -	dBm		
		f = 5000 MHz; Δf = 1 MHz/10 MHz	-	3.0	-	dBm
RL _{in}	input return loss	f = 4400 MHz	-	17.0	-	dB
		f = 5000 MHz	-	14.0	-	dB
RL _{out}	output return loss	f = 4400 MHz	-	15.0	-	dB
		f = 5000 MHz	-	10.0	-	dB
ISL	isolation	f = 4400 MHz	-	22.0	-	dB
		f = 5000 MHz	-	22.0	-	dB

SiGe:C low-noise amplifier with bypass switch for LTE/5G NR

Table 11. Characteristics...continued

4400 MHz \leq f \leq 5000 MHz; V_{CC} = 2.8 V; T_{amb} = 25 °C; input matched 50 Ω using application diagram from Figure 4 and component values as in Table 13. Unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
Bypass m	node		'				
G _p power gain	power gain	f = 4400 MHz	-	-3.6	-	dB	
		f = 5000 MHz	-	-7.0	-	dB	
ISL	isolation	f = 4400 MHz	-	-3.67.0	dB		
			-	dB			
P _{i(1dB)}	input power at 1 dB gain	f = 4400 MHz	-	7.0	-	dBm	
	compression	f = 5000 MHz	-	6.0	-	dBm	
IP3 _i	input third-order intercept point	f = 4400 MHz	-	22.0	-	dBm	
		f = 5000 MHz	-	19.0	-	dBm	
RLin	input return loss	f = 4400 MHz	-	10.0	-	dB	
		f = 5000 MHz	-	6.0	-	dB	
RL _{out}	output return loss	f = 4400 MHz	-	22.0	-	dB	
		f = 5000 MHz	-	21.0	-	dB	
Δφ _{S21}	gain phase step variation	between gain mode and bypass mode					
		f = 4400 MHz	-5.0	-	+5.0	deg	
		f = 5000 MHz	-5.0	-	+5.0	deg	

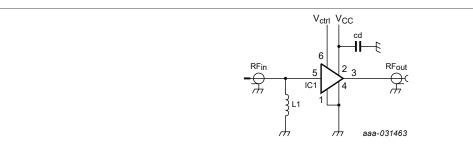
^[1] PCB losses are subtracted.

^[2] Guaranteed by design; not tested in production

SiGe:C low-noise amplifier with bypass switch for LTE/5G NR

13 Application information

13.1 LTE/5G NR application



For a list of components, see <u>Table 12</u>.

Figure 3. Schematics LTE/5G NR evaluation board 3300 MHz-4200 MHz

For improving coexistence in applications, using e.g. LTE B3, refer to Application Note AN11795.

Table 12. List of components For schematics, see Figure 3

Component	Description	Value	Remarks
C _d	decoupling capacitor	1 μF	The total capacitance on the V_{CC} node must be at least 1 μF at a maximum distance of 15 mm from the V_{CC} pin. Typically, such capacitance is already present at the output of the V_{CC} voltage regulator.
IC1	BGS8U5		NXP
L1	high-quality matching inductor	2.2 nH	Murata LQW15A

SiGe:C low-noise amplifier with bypass switch for LTE/5G NR

13.2 5G NR application

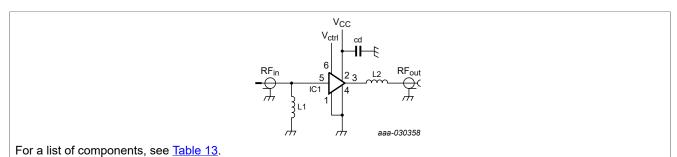


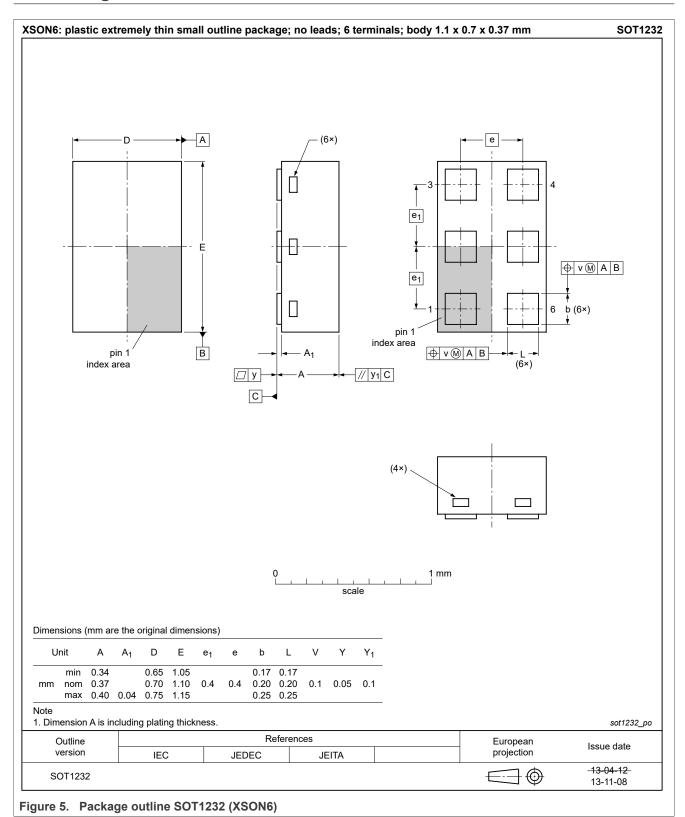
Figure 4. Schematics 5G NR evaluation board 4400 MHz-5000 MHz

Table 13. List of components For schematics, see Figure 4

Component	Description	Value	Remarks
C _d	decoupling capacitor	1 µF	The total capacitance on the V_{CC} node must be at least 1 μF at a maximum distance of 15 mm from the V_{CC} pin. Typically, such capacitance is already present at the output of the V_{CC} voltage regulator.
IC1	BGS8U5		NXP
L1	high-quality matching inductor	2.2 nH	Murata LQW15A
L2	high-quality matching inductor	1.0 nH	Murata LQG15A

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14 Package outline



SiGe:C low-noise amplifier with bypass switch for LTE/5G NR

15 Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices. Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

16 Abbreviations

Table 14. Abbreviations

dulc 14. Approviduolis				
Acronym	Description			
ESD	electrostatic discharge			
НВМ	human body model			
MMIC	monolithic microwave-integrated circuit			
MUF	molded underfill			
LTE	long-term evolution			
5G NR	fifth generation new radio			
PCB	printed-circuit board			
SiGe:C	silicon germanium carbon			

17 Revision history

Table 15. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes			
BGS8U5 v.5	20211201	Product data sheet	-	BGS8U5 v.4			
modification	changed status fro	changed status from Company confidential to Public					
BGS8U5 v.4	20181031	Product data sheet	-	BGS8U5 v.3			
modification	adapted extra freq	adapted extra frequencies and values for different conditions.					
BGS8U5 v.3	20180307	Product data sheet	-	BGS8U5 v.2.0			
modification	min values change	min values changed on RL _{out} parameter in the characteristics chapter					
BGS8U5 v.2.0	20180206	Product data sheet	-	BGS8U5 v.1.3			
modification	min and max value	min and max value added at isolation parameter in the characteristics chapter					
BGS8U5 v.1.3	20180131	Product data sheet	-	BGS8U5 v.1			
BGS8U5 v.1	20171222	Product data sheet	-	-			

SiGe:C low-noise amplifier with bypass switch for LTE/5G NR

18 Legal information

18.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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